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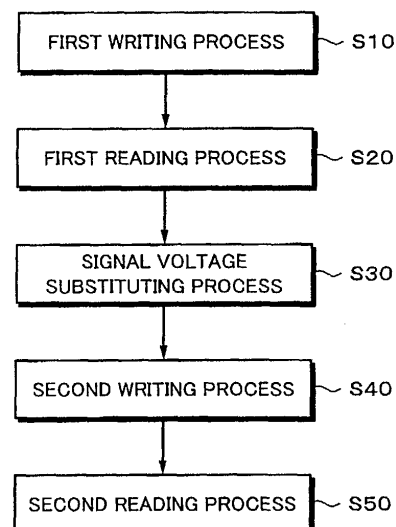
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(54) **Liquid crystal display device and inspecting method thereof**

(57) Output signals of two adjacent data signal lines (DA1 to DAn, DB1 to DBn) are supplied to comparators (CMP1 to CMPn), respectively. When pixels are inspected, different signal potentials are input to signal input terminals (14a and 14b). Signals are written to pixels from the first row to the last row. Thereafter, a pre-charging process is performed by supplying a voltage to the terminals (14a and 14b). Thereafter, signals are read from all the pixels from the first row to the last row. The signal potentials that have been read are compared by the comparators (CMP1 to CMPn). Depending on relations of voltages written as digitally compared outputs of the comparators (CMP1 to CMPn), defective pixels are detected.

Fig. 6



EP 1 441 323 A3



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EUROPEAN SEARCH REPORT

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Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (IPC)
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			TECHNICAL FIELDS SEARCHED (IPC)
			G09G
The present search report has been drawn up for all claims			
Place of search		Date of completion of the search	Examiner
Munich		12 June 2008	Wolff, Lilian
CATEGORY OF CITED DOCUMENTS X : particularly relevant if taken alone Y : particularly relevant if combined with another document of the same category A : technological background O : non-written disclosure P : intermediate document T : theory or principle underlying the invention E : earlier patent document, but published on, or after the filing date D : document cited in the application L : document cited for other reasons & : member of the same patent family, corresponding document			

4

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**ANNEX TO THE EUROPEAN SEARCH REPORT
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This annex lists the patent family members relating to the patent documents cited in the above-mentioned European search report.
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专利名称(译)	液晶显示装置及其检查方法		
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摘要(译)

两个相邻数据信号线 (DA1至DAn , DB1至DBn) 的输出信号分别提供给比较器 (CMP1至CMPn) 。当检查像素时, 不同的信号电位被输入到信号输入端子 (14a和14b) 。信号被写入从第一行到最后一行的像素。此后, 通过向端子 (14a和14b) 提供电压来执行预充电过程。此后, 从第一行到最后一行的所有像素读取信号。通过比较器 (CMP1至CMPn) 比较已读取的信号电位。根据作为比较器 (CMP1至CMPn) 的数字比较输出写入的电压的关系, 检测缺陷像素。

